Wide Temperature Range Version 4M High Speed SRAM (256-kword × 16-bit)

# **HITACHI**

ADE-203-1305A (Z)

Rev. 1.0 Nov. 30, 2001

### **Description**

The HM6216255HCI Series is a 4-Mbit high speed static RAM organized 256-k word  $\times$  16-bit. It has realized high speed access time by employing CMOS process (6-transistor memory cell) and high speed circuit designing technology. It is most appropriate for the application which requires high speed, high density memory and wide bit width configuration, such as cache and buffer memory in system. It is packaged in 400-mil 44-pin plastic SOJ and 400-mil 44-pin plastic TSOPII.

#### **Features**

• Single 5.0 V supply :  $5.0 \text{ V} \pm 10 \%$ 

Access time: 12 ns (max)Completely static memory

— No clock or timing strobe required

Equal access and cycle times

• Directly TTL compatible

— All inputs and outputs

Operating current: 160 mA (max)
TTL standby current: 40 mA (max)

CMOS standby current: 5 mA (max)

• Center V<sub>CC</sub> and V<sub>SS</sub> type pin out

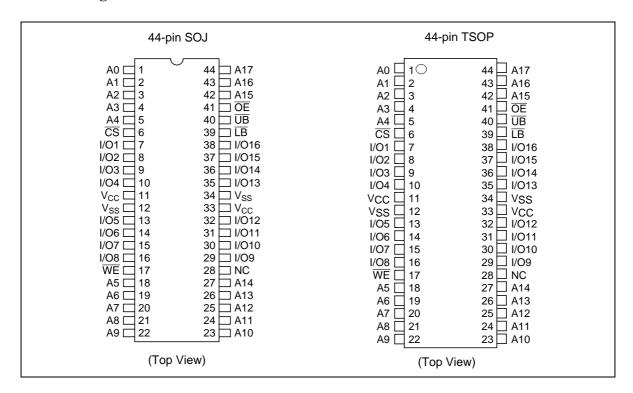
Temperature range : -40 to +85°C

#### **Ordering Information**

Type No.	Access time	Device marking	Package
HM6216255HCJPI-12	12 ns	HM6216255CJPI12	400-mil 44-pin plastic SOJ (CP-44D)
HM6216255HCTTI-12	12 ns	HM6216255CTTI12	400-mil 44-pin plastic TSOPII (TTP-44DE)



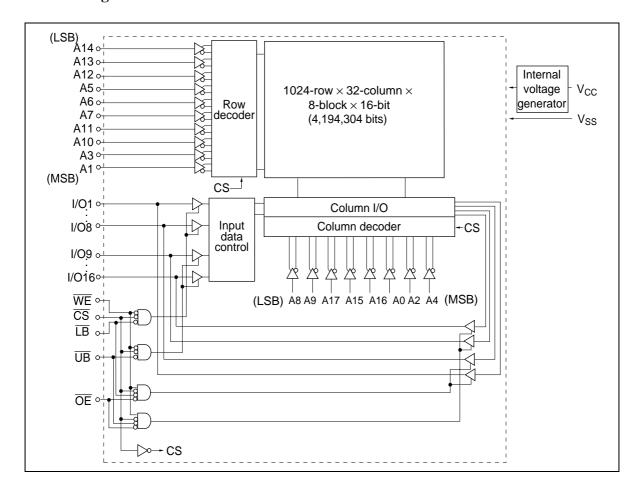
#### **Pin Arrangement**



### **Pin Description**

Pin name	Function
A0 to A17	Address input
I/O1 to I/O16	Data input/output
CS	Chip select
ŌĒ	Output enable
WE	Write enable
<del>UB</del>	Upper byte select
LB	Lower byte select
V <sub>CC</sub>	Power supply
V <sub>SS</sub>	Ground
NC	No connection

### **Block Diagram**



# **Operation Table**

<del>CS</del>	OE	WE	LB	<del>UB</del>	Mode	V <sub>CC</sub> current	I/O1-I/O8	I/O9-I/O16	Ref. cycle
Н	×	×	×	×	Standby	I <sub>SB</sub> , I <sub>SB1</sub>	High-Z	High-Z	_
L	Н	Н	×	×	Output disable	I <sub>CC</sub>	High-Z	High-Z	_
L	L	Н	L	L	Read	Icc	Output	Output	Read cycle
L	L	Н	L	Н	Lower byte read	Icc	Output	High-Z	Read cycle
L	L	Н	Н	L	Upper byte read	I <sub>CC</sub>	High-Z	Output	Read cycle
L	L	Н	Н	Н	_	Icc	High-Z	High-Z	_
L	×	L	L	L	Write	Icc	Input	Input	Write cycle
L	×	L	L	Н	Lower byte write	I <sub>CC</sub>	Input	High-Z	Write cycle
L	×	L	Н	L	Upper byte write	I <sub>CC</sub>	High-Z	Input	Write cycle
L	×	L	Н	Н	_	Icc	High-Z	High-Z	_

Note: H: V<sub>IH</sub>, L: V<sub>IL</sub>, ×: V<sub>IH</sub> or V<sub>IL</sub>

### **Absolute Maximum Ratings**

Parameter	Symbol	Value	Unit
Supply voltage relative to V <sub>SS</sub>	V <sub>CC</sub>	-0.5 to +7.0	V
Voltage on any pin relative to V <sub>SS</sub>	V <sub>T</sub>	$-0.5^{*1}$ to $V_{CC} + 0.5^{*2}$	V
Power dissipation	P <sub>T</sub>	1.0	W
Operating temperature	Topr	-40 to +85	°C
Storage temperature	Tstg	-55 to +125	°C
Storage temperature under bias	Tbias	-40 to +85	°C

Notes: 1.  $V_T$  (min) = -2.0 V for pulse width (under shoot)  $\leq$  6 ns.

<sup>2.</sup>  $V_T$  (max) =  $V_{CC}$  + 2.0 V for pulse width (over shoot)  $\leq$  6 ns.

### **Recommended DC Operating Conditions**

 $(Ta = -40 \text{ to } +85^{\circ}C)$ 

Parameter	Symbol	Min	Тур	Max	Unit	
Supply voltage	V <sub>CC</sub> * <sup>3</sup>	4.5	5.0	5.5	V	
	V <sub>SS</sub> * <sup>4</sup>	0	0	0	V	
Input voltage	V <sub>IH</sub>	2.2	_	V <sub>CC</sub> + 0.	5* <sup>2</sup> V	
	$\overline{V_IL}$	-0.5* <sup>1</sup>	_	0.8	V	

Notes: 1.  $V_{IL}$  (min) = -2.0 V for pulse width (under shoot)  $\leq$  6 ns.

- 2.  $V_{IH}$  (max) =  $V_{CC}$  + 2.0 V for pulse width (over shoot)  $\leq$  6 ns.
- 3. The supply voltage with all  $V_{\text{CC}}$  pins must be on the same level.
- 4. The supply voltage with all  $V_{\mbox{\footnotesize SS}}$  pins must be on the same level.

#### **DC** Characteristics

(Ta = -40 to +85°C,  $V_{CC} = 5.0 \text{ V} \pm 10 \text{ %}, V_{SS} = 0 \text{ V}$ )

Parameter	Symbol	Min	Typ* <sup>1</sup>	Max	Unit	Test conditions
Input leakage current	I <sub>LI</sub>	_	_	2	μΑ	Vin = V <sub>SS</sub> to V <sub>CC</sub>
Output leakage current*1	I <sub>LO</sub>	_	_	2	μΑ	Vin = V <sub>SS</sub> to V <sub>CC</sub>
Operating power supply current	I <sub>CC</sub>	_	_	160	mA	$\overline{\text{CS}} = \text{V}_{\text{IL}}, \text{ lout} = 0 \text{ mA}$ Other inputs = $\text{V}_{\text{IH}}/\text{V}_{\text{IL}}$
Standby power supply current	I <sub>SB</sub>	_	_	40	mA	CS = V <sub>IH</sub> , Other inputs = V <sub>IH</sub> /V <sub>IL</sub>
	I <sub>SB1</sub>	_	2.5	5	mΑ	$Vcc \ge \overline{CS} \ge Vcc - 0.2 V$ ,
						(1) $0 \text{ V} \le \text{Vin} \le 0.2 \text{ V} \text{ or}$
						(2) $V_{CC} \ge Vin \ge V_{CC}$ - 0.2 V
Output voltage	V <sub>OL</sub>	_	_	0.4	V	I <sub>OL</sub> = 8 mA
	V <sub>OH</sub>	2.4	_	_	V	$I_{OH} = -4 \text{ mA}$

Note: 1. Typical values are at  $V_{CC} = 5.0 \text{ V}$ ,  $Ta = +25^{\circ}\text{C}$  and not guaranteed.

### Capacitance

 $(Ta = +25^{\circ}C, f = 1.0 \text{ MHz})$ 

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions
Input capacitance*1	Cin	_	_	6	pF	Vin = 0 V
Input/output capacitance*1	C <sub>I/O</sub>	_	_	8	pF	V <sub>I/O</sub> = 0 V

Note: 1. This parameter is sampled and not 100% tested.

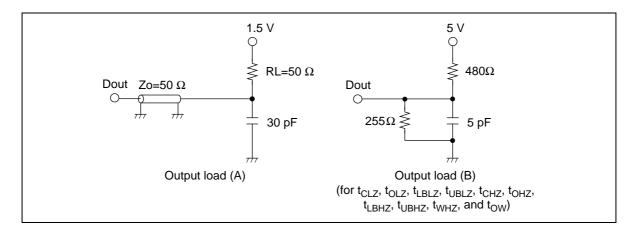
#### **AC Characteristics**

(Ta = -40 to +85°C,  $V_{CC}$  = 5.0 V  $\pm$  10 %, unless otherwise noted.)

#### **Test Conditions**

Input pulse levels: 3.0 V/0.0 V
Input rise and fall time: 3 ns

Input and output timing reference levels: 1.5 VOutput load: See figures (Including scope and jig)



### **Read Cycle**

#### HM6216255HCI

-12

Parameter	Symbol	Min	Max	Unit	Notes	
Read cycle time	t <sub>RC</sub>	12	_	ns		
Address access time	t <sub>AA</sub>	_	12	ns		
Chip select access time	t <sub>ACS</sub>	_	12	ns		
Output enable to output valid	t <sub>OE</sub>	_	6	ns		
Byte select to output valid	t <sub>LB</sub> , t <sub>UB</sub>	_	6	ns		
Output hold from address change	t <sub>OH</sub>	3	_	ns		
Chip select to output in low-Z	t <sub>CLZ</sub>	3	_	ns	1	
Output enable to output in low-Z	t <sub>OLZ</sub>	0	_	ns	1	
Byte select to output in low-Z	t <sub>LBLZ</sub> , t <sub>UBLZ</sub>	: 0	_	ns	1	
Chip deselect to output in high-Z	t <sub>CHZ</sub>	_	6	ns	1	
Output disable to output in high-Z	t <sub>OHZ</sub>	_	6	ns	1	
Byte deselect to output in high-Z	t <sub>LBHZ</sub> , t <sub>UBH</sub> ;	z —	6	ns	1	

#### Write Cycle

#### HM6216255HCI

-12

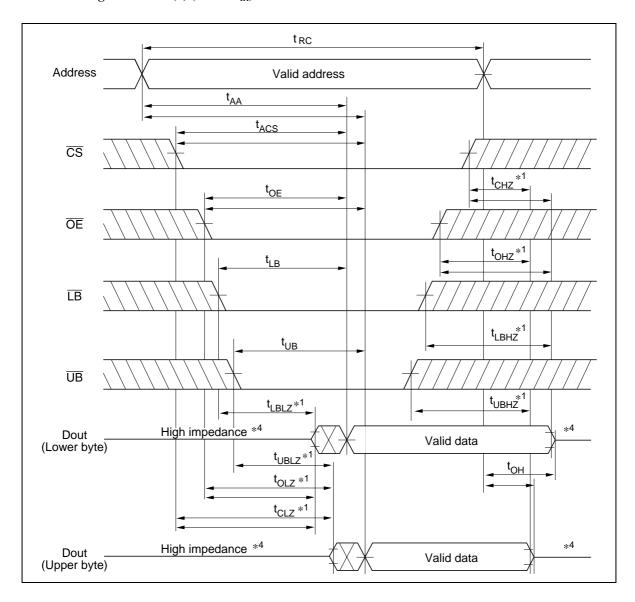
Parameter	Symbol	Min	Max	Unit	Notes	
Write cycle time	twc	12	_	ns		
Address valid to end of write	t <sub>AW</sub>	8	_	ns		
Chip select to end of write	t <sub>CW</sub>	8	_	ns	8	
Write pulse width	t <sub>WP</sub>	8	_	ns	7	
Byte select to end of write	t <sub>LBW</sub> , t <sub>UBW</sub>	8	_	ns	9, 10	
Address setup time	t <sub>AS</sub>	0	_	ns	5	
Write recovery time	t <sub>WR</sub>	0	_	ns	6	
Data to write time overlap	t <sub>DW</sub>	6	_	ns		
Data hold from write time	t <sub>DH</sub>	0	_	ns		
Write disable to output in low-Z	t <sub>OW</sub>	3	_	ns	1	
Output disable to output in high-Z	t <sub>OHZ</sub>	_	6	ns	1	
Write enable to output in high-Z	t <sub>WHZ</sub>	_	6	ns	1	

Notes: 1. Transition is measured ±200 mV from steady voltage with output load (B). This parameter is sampled and not 100% tested.

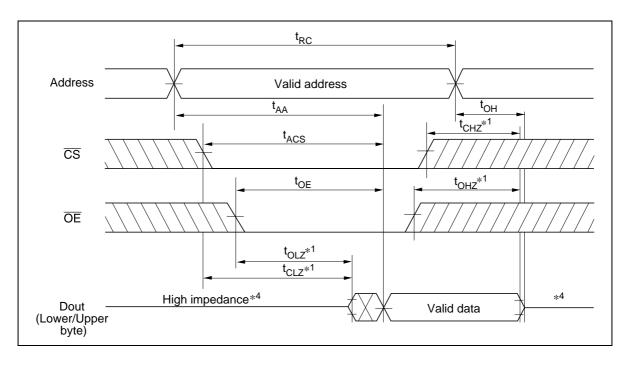
- 2. If the  $\overline{\text{CS}}$  or  $\overline{\text{LB}}$  or  $\overline{\text{UB}}$  low transition occurs simultaneously with the  $\overline{\text{WE}}$  low transition or after the  $\overline{\text{WE}}$  transition, output remains a high impedance state.
- 3. WE and/or CS must be high during address transition time.
- 4. If  $\overline{\text{CS}}$ ,  $\overline{\text{OE}}$ ,  $\overline{\text{LB}}$  and  $\overline{\text{UB}}$  are low during this period, I/O pins are in the output state. Then the data input signals of opposite phase to the outputs must not be applied to them.
- 5. t<sub>AS</sub> is measured from the latest address transition to the latest of  $\overline{CS}$ ,  $\overline{WE}$ ,  $\overline{LB}$  or  $\overline{UB}$  going low.
- 6.  $t_{WR}$  is measured from the earliest of  $\overline{CS}$ ,  $\overline{WE}$ ,  $\overline{LB}$  or  $\overline{UB}$  going high to the first address transition.
- 7. A write occurs during the overlap of low  $\overline{CS}$ , low  $\overline{WE}$  and low  $\overline{LB}$  or low  $\overline{UB}$ .
- 8.  $t_{CW}$  is measured from the later of  $\overline{CS}$  going low to the end of write.
- 9.  $t_{LBW}$  is measured from the later of  $\overline{LB}$  going low to the end of write.
- 10.  $t_{UBW}$  is measured from the later of  $\overline{UB}$  going low to the end of write.

# **Timing Waveforms**

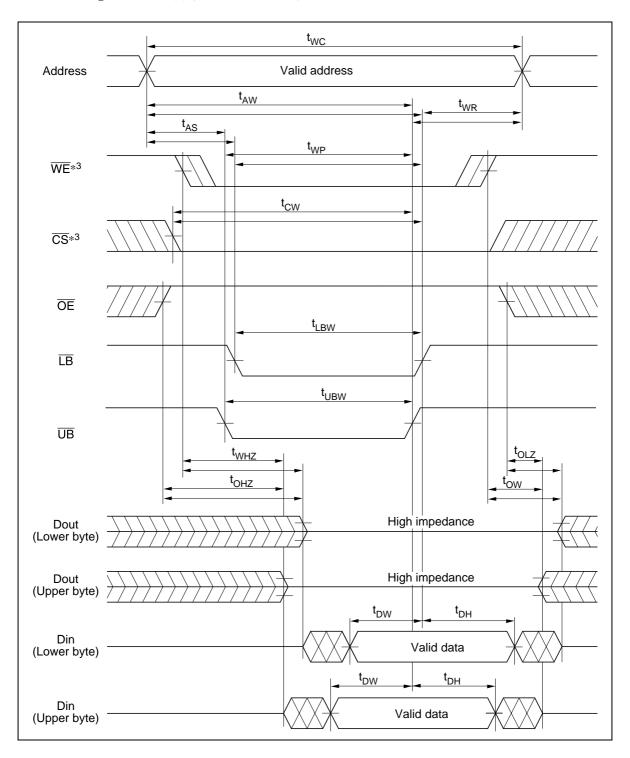
**Read Timing Waveform** (1)  $(\overline{WE} = V_{IH})$ 



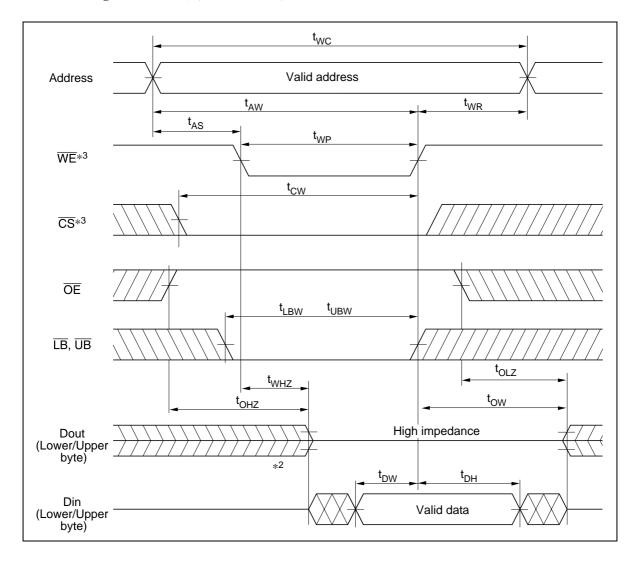
Read Timing Waveform (2)  $(\overline{WE}=V_{IH},\,\overline{LB}=V_{IL},\,\overline{UB},=V_{IL})$ 



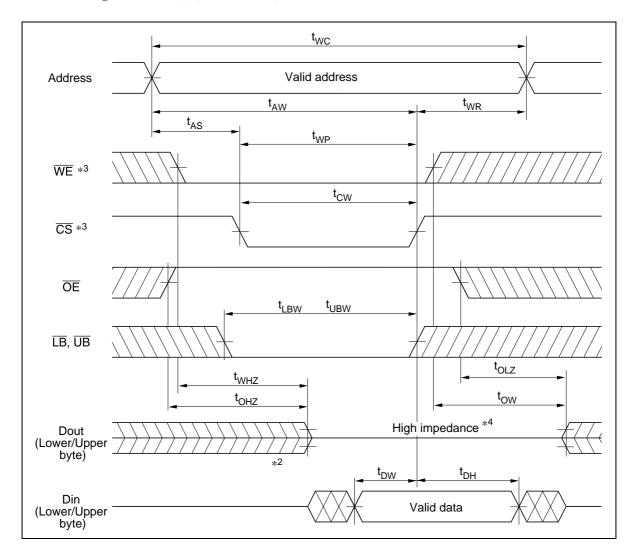
Write Timing Waveform (1) (LB, UB Controlled)



# Write Timing Waveform (2) (WE Controlled)

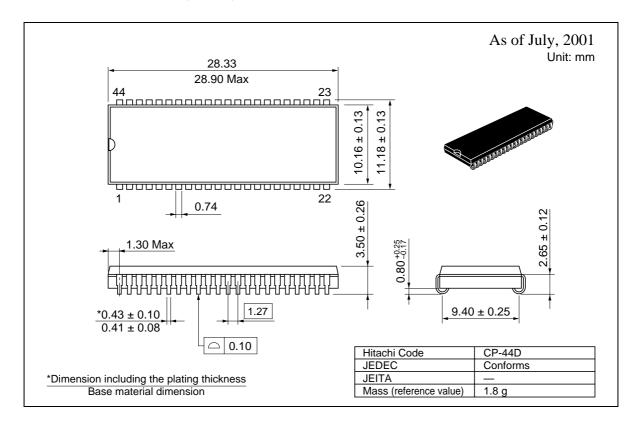


# Write Timing Waveform (3) (CS Controlled)

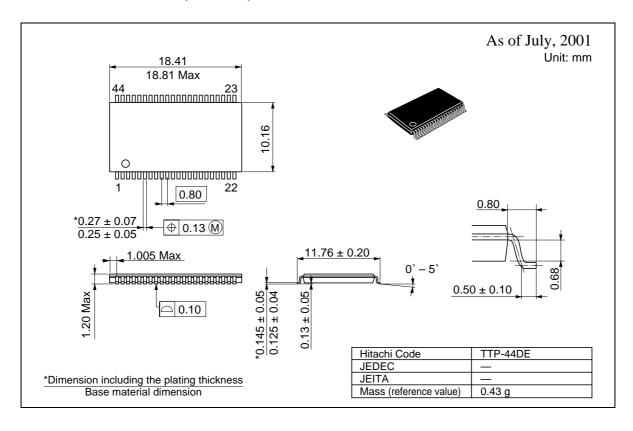


### **Package Dimensions**

#### HM6216255HCJPI Series (CP-44D)



#### HM6216255HCTTI Series (TTP-44DE)



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